

Search Notes



Application/Control No.

10/817,191

Examiner

Randall Chin

Applicant(s)/Patent under Reexamination

MEYERS, LAWRENCE G.

Art Unit

1744

SEARCHED

Class	Subclass	Date	Examiner
15	235.4		
15	235.5		
15	235.6		
15	235.7		
15	235.8		
15	245.1		
15	145	9/6/2007	RC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
PG-PUB	TEXT		
SRCH - SEE			
SRCH HISTORY			
PRINTOUT		9/6/07	RC

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST, OCR, EPO, JPO, DERWENT		
Inventor name search	9/6/2007	RC